Specifications

Optics	CFI60 optics
Observation image	Upright back image
Observation method	Brightfield and simple polarizing (when using MA-P/A Simple Polarizing Set)
Focusing section	Vertical action revolver (fixed stage)
	Single-axis coarse/fine adjustment handle with 8.5mm stroke (coarse adjustment of 37.7mm per turn, fine adjustment of 0.2mm per turn)
Nosepiece	Brightfield 5-position nosepiece
Stage	MA-SP Plain Stage: 170 x 230mm (includes two holders for acrylic samples ¢30mm aperture, crescent aperture)
	Can be combined with MA-SRSH1 Universal Specimen Holder or MA-SH3 Specimen Holder 3.
	TI-SM Mechanical Stage CH: 126 x 80mm stroke; Handle can be attached on the right or left side of the stage
	Can be combined with MA-SH1 Specimen Holder 1, MA-SH2 Specimen Holder 2, or C-HU Universal Holder.
	MA-SR Rectangular Stage: 50 x 50mm stroke (includes two sample holders at ¢20mm and 40mm apertures) and handle fixed on right side.
	Can be combined with MA-SRSH1 Universal Specimen Holder or MA-SH3 Specimen Holder 3.
Illuminator	Internal power supply 6V 30W Halogen Lamp (long-life type)
	Condenser built-in (lever operated)
Eyepiece tube	Built-in mirror type, 45° depression angle and 50 to 75mm interpupillary adjustment
Max. power consumption	96VA
External dimensions	228 x 663 x 382 mm (W x D x H)
Weight	Approx. 9kg

Dimensions (mm)





23

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. October 2006 NIKON CORPORATION

45 110

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TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING THE EQUIPMENT. BA NIKON CORPORATION Parale Mitsui Bldg., 8, Higashida-cho, Kawasaki-ku, Kawasaki, Kanagawa 210-0005, Japan

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Code No. 2CE-KVNH-1

En

Introducing a durable, user-friendly microscope with a small footprint, superior image quality, and great cost performance

The ECLIPSE MA100 is a compact-size inverted microscope specially designed for reflected illumination. This instrument was developed for brightfield observation and simple polarizing observation. Thanks to its compact, durable design, simple operation, and high-contrast observation and image capture, it is excellent for metallographic and electronic components as well as use at product sites in the materials field and guality control departments.

Aperture Diaphragm

Comes standard with a condenser

The epi illuminator comes standard with a condenser which enables users to control image contrast and depth of field of the sample.



Polarizer/Analyzer

Simple polarization observation with a single-action polarizer/analyzer mechanism.

This device makes possible simple polarizing observation, which is effective for samples such as polymer materials. It takes just a single action to engage the polarizer and analyzer in the light path. The polarizer can rotate 360° degrees, allowing users to set a polarization direction suited to the sample being observed.

Stage

Stable control even with heavy samples A newly developed stage boasting superior durability

Nikon developed the all-new MA-SR Rectangular Stage especially for the MA100. The three-plate structure gives the microscope stable control and superior durability and enables observation of heavy samples, including embedded samples that are still mounted on a grinder's holder.



CFI60

Sharp, clear images using CFI60 optics

Nikon's proprietary CFI60 optics provide high NA and a longer working distance. CFI60 optics deliver bright. high-resolution images. Up to five objective lenses can be mounted





Mirror-

Identify objective magnification at a glance with an adjustable mirror.

The ECLIPSE MA100 ships complete with a mirror for checking objective lenses, which makes observation much more efficient. Now users can verify what objective lens is being used as well as the observation position of the sample in a comfortable

position, without having to look beneath the stage.





Digital Sight Series

A flexible system that enables various configurations consisting of a camera head and a control unit to suit the needs of each sample or application.



Camera Heads



High-difinit	ion color came	ra head D	5-F	-i1 🥪	t+ ↓+ High Resolution
Imag	e sensor	Max. recordable pixe	ls Cooling	Display speed	Sensitivity
5-megapixel 2	/3-inch color CCD	2,560 x 1.920	None	5.9 to 23 fps	Equivalent to ISO 64

The DS-Fi1 features a 5-megapixel CCD that can faithfully capture 2,560 x 1,920-pixel high-resolution images. This camera head features frame rates far beyond conventional models with improved image quality and ease of use, including a refined IR cut filter. Advanced functionality and high cost performance are the hallmarks of the DS-Fi1.



High-speed color camera	head DS -	20	1v 🖤	High Speed
				117 L
High-speed color camera	head			Speed
ingii-speed color camera				Speed

Image sensor	Max. recordable pixels	Cooling	Display speed	Sensitivity
2-megapixel 1/1.8-inch color CCD	1,600 x 1,200	None	5.0 to 30 fps	Equivalent to ISO 100

The DS-2Mv features a 2-megapixel CCD that displays SXGA video at a high frame rate of 15 fps*1 (max. 30fps). This camera head enables the smooth display of live images and the capture of crystal-clear still images with a high sensitivity. With the exceptionally high frame rates it can even be used for live monitoring. *1) When using DS-L2 and outputting to an external monitor.

* In addition to these camera heads, Nikon also has a variety of other models, such as the DS-5Mc high-definition camera head with a built-in cooling mechanism.

Camera Control Unit

PC-Based Control Unit **DS-U2**

The DS-U2 controls everything from live image display and capture to advanced image processing and analysis on a computer. It supports a wide range of applications.

Simple connection via high-speed USB 2.0

The U2 control unit employs a USB 2.0 interface for connecting with a PC. It makes operation with a PC seamless and improves transfer speed up to 1.6 faster than previous models.



NIS-Elements series

of newly developed image integration software

The NIS-Elements series is used for the control software. This software allows the user to perform everything from basic image capture to the measurement, analysis, and management of captured images. Users can add a wide array of the plug-ins to basic packages according to their intended use.

				5	: Standard	O: Optional
		Main fur	nctions of each package	F	D	Br
NIS-Elements F Package Free bundle			Enlarge/reduce, full screen, and magnifying glass	S	S	S
This postage englated display of a scale over a live image, quitabing to full			Capture thumbnail	S	S	S
I his package enables display of a scale over a live image, switching to full-			Scale, annotation, and profile	S (live)	S	S
screen display, and	other functions. It allows the user to easily capture images		Grid		S	S
with a simple intuitiv	e control screen.		LUT, histogram, and sequence replay		S	S
			3D surface model		0	0
	Standard set	Image	Auto-capture	S	S	<u> </u>
NIS-Eleme	ents Documentation	capture	Multi-dimensional support		3D	4D
This package provid	as functions for performing measurements and creating		Time lapse		Individual	Multi
This package provid			Z series and multi-point		5	5
reports. Use it for ge	neral microimage capture in the industrial field.		Large IIIage		5	5
Expandability is also	possible by adding plug-ins, such as EDF and databases.	Data	BMP TIFE IPEG and IPEG2000	6	s	<u> </u>
		formats	GIE PNG ICS/IDS and original format		<u> </u>	<u> </u>
		Imane	White balance and tone	s	S	S
NIS-Eleme	ents Basic Research Option	processing	LUT and shading correction		s	s
In addition to the me	acurement function and report generating function of NIS-		Contrast and hue/saturation correction	S	s	s
			Edge enhancement, averaging, and smoothing		S	S
Elements Document	ation, this package enables automatic object		EDF and realtime EDF		0	S
measurement by creating a binary image. Expandability is also possible by		lmage editing	Сгор	S	S	S
adding plug-ins, such as EDF and databases.			Image overlay	3 (RGB)	4 (RGB+ α)	Multi-channel
			Cut, copy, paste, rotate, invert, and resize		S	S
			Component extraction		S	S
Operating environment			Pseudo-color		S	S
The following PC environment is recommended for maximizing the performance		Image	Calibration (length)	S	S	S
of NIS-Elements		analysis	Manual measurement (count, length, area, angle, circle, and ellipse)		S	S
			Auto-measurement (digitization and object extraction)		0	S
CPU	3.2GHz Intel [®] Pentium [®] IV processor or better		3D measurement (EDF)		0	0
RAM	1GB or more		Time measurement			0
		Peripheral device control	Microscope control		S	s
OS	Microsoft Windows XP SP2 (English version)	Corcor	Control of other companies devices		0	0
Hard disk space	600MB or more required for installation	control	Lavout manager		5	5
Display	1280 x 1024 or better (TrueColor mode)		Customize		0	0
		Other	Printing, PDF output, mail transmission	S	S	S
			Optical configuration		S	S
Application window F (There is no organizer window) D Br			Report generator		S	S
			Macros		S	S
Freely select the window layout according to the purpose at hand.				S	0	
Window style			SDI	SDI(Japanese)	MDI	

CPU	3.2GHz Intel [®] Pentium [®] IV processor or better
RAM 1GB or more	
OS	Microsoft [®] Windows [®] XP SP2 (English version)
Hard disk space	600MB or more required for installation
Display	1280 x 1024 or better (TrueColor mode)







Measure quantity, length, radius, angle, area, and pixel intensity profile.

D Br

Report generator

Create reports containing images, database descriptions, and measured data. PDF files can be created directly from NIS-Elements.





Databases (Plug-in D Br

Users can easily create a variety of databases, file types and store images with a simple click of the mouse. Image categorization is easier than ever before.



Plug-in D Br EDF (Extended Depth of Focus)

Create reports containing images, database descriptions, and measured data. PDF files can be created directly from NIS-Elements.



Digital Sight Series (2)

Stand-alone Control Unit **DS-L2**

The DS-L2 features a large high-definition LCD and a host of features. There is no need for a PC and monitor, which allows the system to be used with a flick of a switch.

Large, high-definition monitor

The unit has a built-in 8.4-inch TFT LCD monitor with 1,024 x 786 pixels, a brightness of 350cd/m², and 400:1 contrast.

Handy save/print features

The unit enables data to be saved on USB memory sticks, as well as on CF cards and microdrives, transferred through a network path. In addition, it comes standard with direct printing to PictBridge printers. It also features "Real 10" modes that make it possible to set and adjust print scaling.

Easy-to-use toolbar

Frequently used features are displayed as toolbar buttons. This enables control without hampering the display of the image to be captured. It is also possible to customize the buttons.



Scene mode: optimal image capture with a single button

The unit features three scene modes for industrial samples. These modes all offer capture conditions optimized for the particular sample type. Users can also register up to seven freely configurable custom modes.



-Accessory -

Stages + Holders







MA-SR Rectangular Stage Specimen Holder (standard accessory/¢20mm aperture) MA-SH3 Specimen Holder 3 MA-SRSH1 Specimen Holder (standard accessory/ ϕ 40mm aperture)

Objective Lenses

An extensive array of tool functions

X0

Angle

•Measurement and alignment function

measurement data.

Measurement functions

•Drawing functions

Superimposition

Count markers
Text entry

.....

Distance between two points

seven types can be registered).

Scale display/alignment functions

Scale XY scale Screen pattern

1

oint-to-line distance

• Straight lines (Arrows can be set.) • Curves

(semitransparent image overlay for comparative purpo

Users can measure captured images and enter line contrast and other settings

Measurement and alignment is possible by standard-length calibration (up to

Grid I

Users can input and display lines, comments, and other useful elements.

 \bigcirc

using the overlay. Users can also save data in image files and output



Grain Size Reticle

Line

Mark

Superimposition

🏇 Pen

T Text

CEIm ontics objective lens

Туре	Power	Numerical aperture(NA)	Working distance (W.D.)(mm)			
CFI L Plan EPI	2.5x	0.075	8.8			
CFI LU Plan Fluor EPI	5x	0.15	23.5			
	10x	0.30	17.5			
	20x	0.45	4.5			
	50x	0.80	1.0			
	100x	0.90	1.0			
CFI LU Plan EPI ELWD	20xA	0.40	13.0			
	50xA	0.55	10.1			
	100xA	0.80	3.5			
CFI L Plan EPI SLWD	20x	0.35	24.0			
	50x	0.45	17.0			
	100x	0.70	6.5			
CFI LU Plan Apo EPI	100x	0.95	0.4			
	150x	0.95	0.3			
CFI L Plan Apo EPI WI	150x	1.25	0.25			

Simple polarizer



System Diagram







MA-SP Plain Stage 2 Acrylic Sample Holder (standard accessory/d30mm aperture) 3 MA-SH3 Specimen Holder 3 MA-SRSH1 Universal Specimen Holder G Acrylic Sample Holder (standard accessory/crescent aperture)

TI-SM Mechanical Stage CH 2C-HU Universal Holder 3 MA-SH1 Specimen Holder 1 MA-SH2 Specimen Holder 2 * Use in combination with the MA-SP Plain Stage.





6